## Application/Control No. 10/721,875 Examiner Alex Liew Document Number Applicant(s)/Patent Under Reexamination ENDO ET AL. Page 1 of 1 U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0021462	01-2003	Sakai et al.	382/144
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## FOREIGN PATENT DOCUMENTS

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